Application/Control No. Applicant(s)/Patent Under Reexamination 10/016,853 LIN ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 David Q. Nguyen 2681 **U.S. PATENT DOCUMENTS** Document Number Date Name Classification Country Code-Number-Kind Code MM-YYYY US-Α US-В С US-US-D Ε US-US-F G US-US-

FOREIGN PATENT DOCUMENTS

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